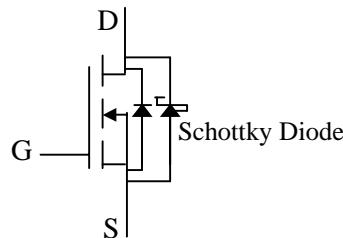




- ▼ Simple Drive Requirement
- ▼ Good Recovery Time
- ▼ Small Size & Lower Profile
- ▼ RoHS Compliant & Halogen-Free

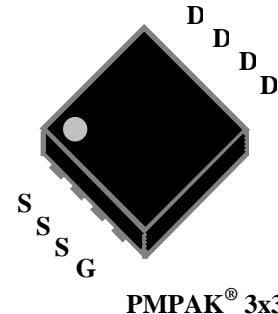


BV_{DSS}	30V
$R_{DS(ON)}$	7.2mΩ
I_D	17.5A

Description

AP4034A series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The PMPAK® 3x3 package is special for voltage conversion application using standard infrared reflow technique with the backside heat sink to achieve the good thermal performance.



PMPAK® 3x3

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current ³	17.5	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current ³	14	A
I_{DM}	Pulsed Drain Current ¹	60	A
V_{KA}	Schottky Reverse Voltage	30	V
$I_F @ T_A=25^\circ C$	Continous Forward Current	1	A
I_{FM}	Pulsed Diode Forward Current	25	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	3.57	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-c}	Maximum Thermal Resistance, Junction-case	5	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	35	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=12\text{A}$	-	5.8	7.2	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=8\text{A}$	-	8.2	10.8	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	1.4	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=12\text{A}$	-	29	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	100	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge	$I_{\text{D}}=12\text{A}$	-	17	27	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=15\text{V}$	-	4.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	7.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=15\text{V}$	-	10	-	ns
t_r	Rise Time		-	5	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time		-	32	-	ns
t_f	Fall Time		-	7.5	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2000	3200	pF
C_{oss}	Output Capacitance		-	230	-	pF
C_{rss}	Reverse Transfer Capacitance		-	170	-	pF
R_g	Gate Resistance	$f=1.0\text{MHz}$	-	1.1	2.2	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Diode+Schottky Forward On Voltage ²	$I_{\text{S}}=1.0\text{A}, V_{\text{GS}}=0\text{V}$	-	0.48	0.5	V
t_{rr}	Body Diode+Schottky Reverse Recovery Time	$I_{\text{S}}=12\text{A}, V_{\text{GS}}=0\text{V},$ $dI/dt=100\text{A}/\mu\text{s}$	-	22	-	ns
Q_{rr}	Body Diode+Schottky Reverse Recovery Charge		-	15	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² 2oz copper pad of FR4 board, $t \leq 10\text{sec}$, $160^\circ\text{C}/\text{W}$ when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

APEC DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

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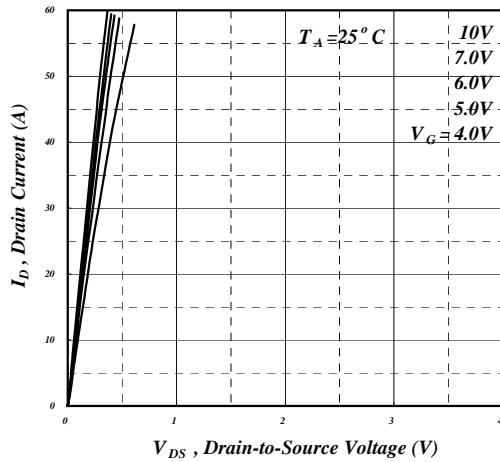


Fig 1. Typical Output Characteristics

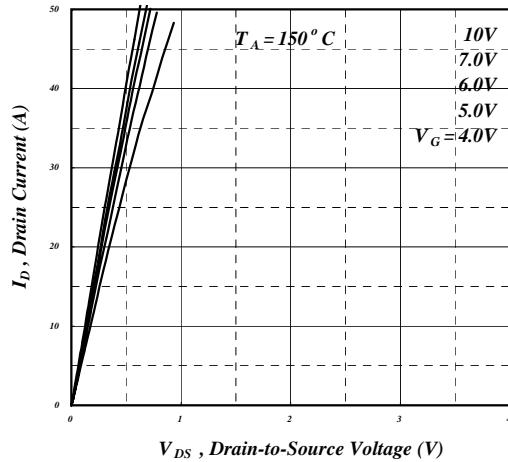


Fig 2. Typical Output Characteristics

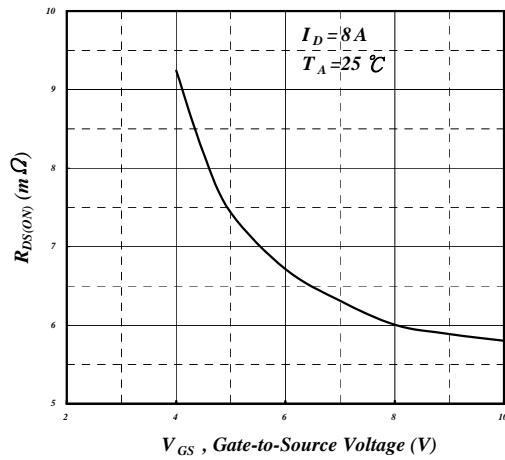


Fig 3. On-Resistance v.s. Gate Voltage

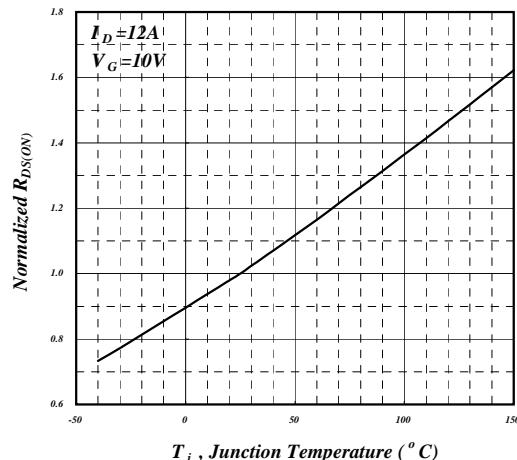


Fig 4. Normalized On-Resistance v.s. Junction Temperature

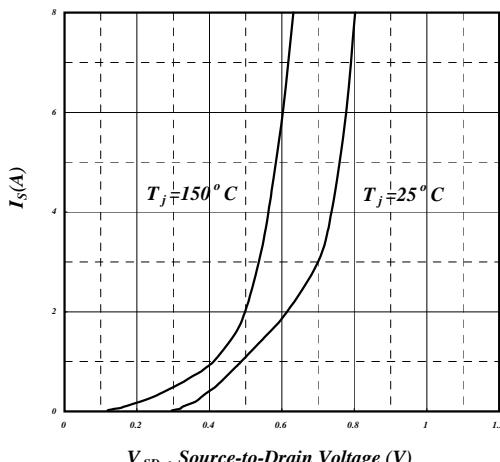


Fig 5. Forward Characteristic of Reverse Diode

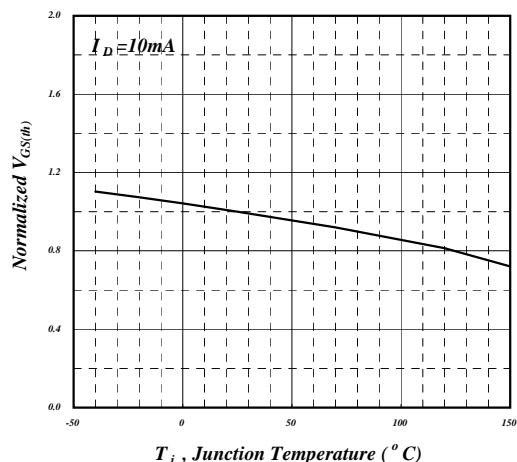


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

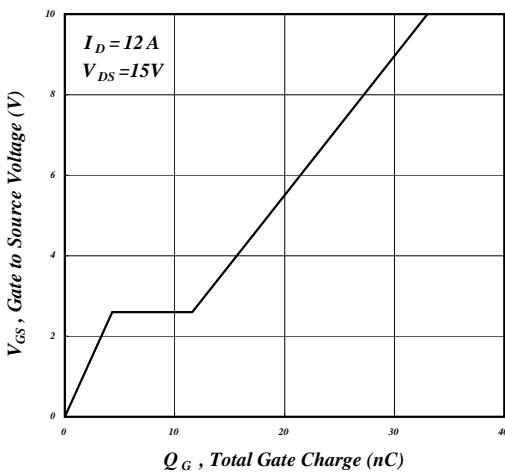


Fig 7. Gate Charge Characteristics

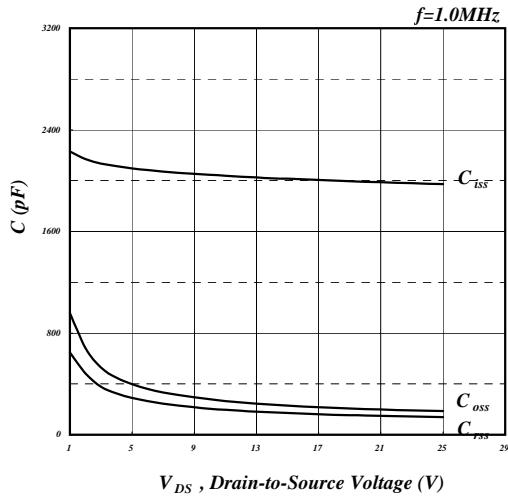


Fig 8. Typical Capacitance Characteristics

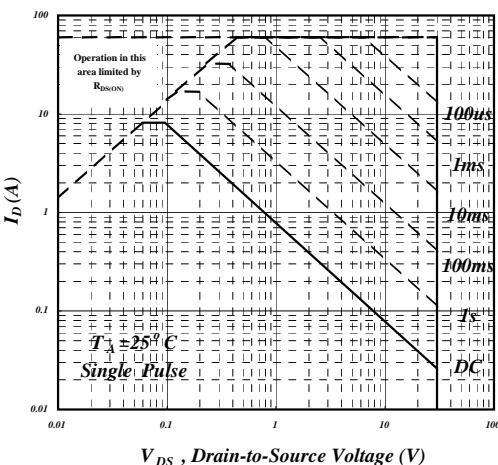


Fig 9. Maximum Safe Operating Area

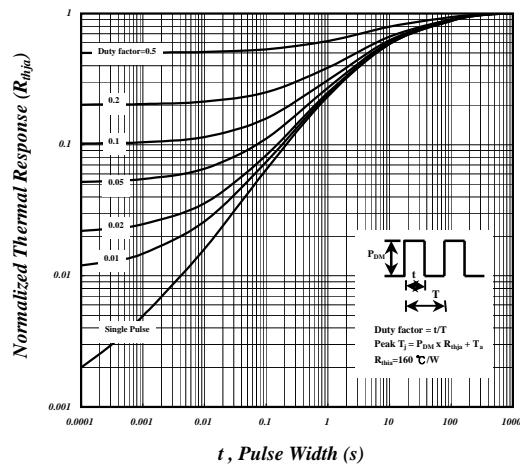


Fig 10. Effective Transient Thermal Impedance

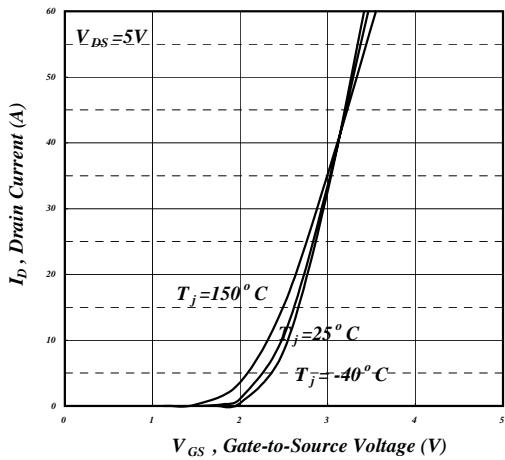


Fig 11. Transfer Characteristics

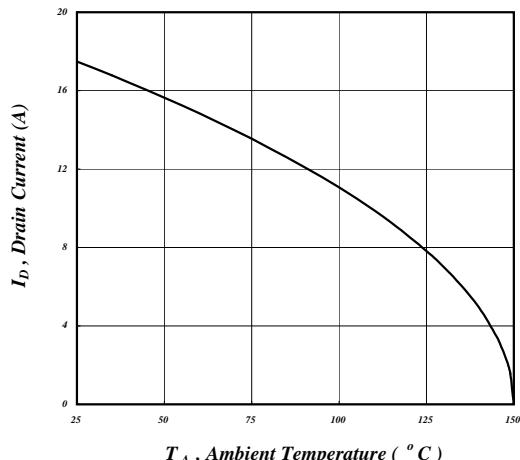


Fig 12. Maximum Continuous Drain Current v.s. Ambient Temperature